

09/869274

JC18 Re CT/PTO 26 JUN 2001 of 2

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. H-987		SERIAL NO.		
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT A. NISHIMURA et al				
				FILING DATE June 26, 2001		GROUP		
U.S. PATENT DOCUMENTS								
* EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)	
AA	6,030,890	2/29/00	Iwabuchi					
AB	6,008,543	12/28/99	Iwabuchi					
AC	5,554,940	9/10/96	Hubacher					
AD								
AE								
AF								
AG								
AH								
AI								
AJ								
AK								
FOREIGN PATENT DOCUMENTS								
		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
AL	4-26537	3/3/92	Japan				<input type="checkbox"/>	<input type="checkbox"/>
AM	4-96343	3/27/92	Japan				<input type="checkbox"/>	<input type="checkbox"/>
AN	5-218042	8/27/93	Japan				<input type="checkbox"/>	<input type="checkbox"/>
AO	8-250498	9/27/96	Japan				<input type="checkbox"/>	<input type="checkbox"/>
AP	8-64633	3/8/96	Japan				<input type="checkbox"/>	<input type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)								
AR		IEEE/CPMT INTL ELECTRONICS MANUFACTURING TECHNOLOGY SYMPOSIUM, "Impact of Wafer Probe Damage on Flip Chip Yields and Reliability", M. Varnau et al, pp. 293-297.						
AS								
AT								
EXAMINER				DATE CONSIDERED				
Miller-Dal				12/10/02				

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U.S. PATENT DOCUMENTS							
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	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES NO
	AL	8-340029	12/24/96	Japan			<input type="checkbox"/> <input type="checkbox"/>
	AM	8-29451	2/2/96	Japan			<input type="checkbox"/> <input type="checkbox"/>
	AN						<input type="checkbox"/> <input type="checkbox"/>
	AO						<input type="checkbox"/> <input type="checkbox"/>
	AP						<input type="checkbox"/> <input type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
	AR						
	AS						
	AT						
EXAMINER <i>William D. O'Connell</i>				DATE CONSIDERED <i>12/18/02</i>			